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# Assessment of Organic Residues on Medical Devices

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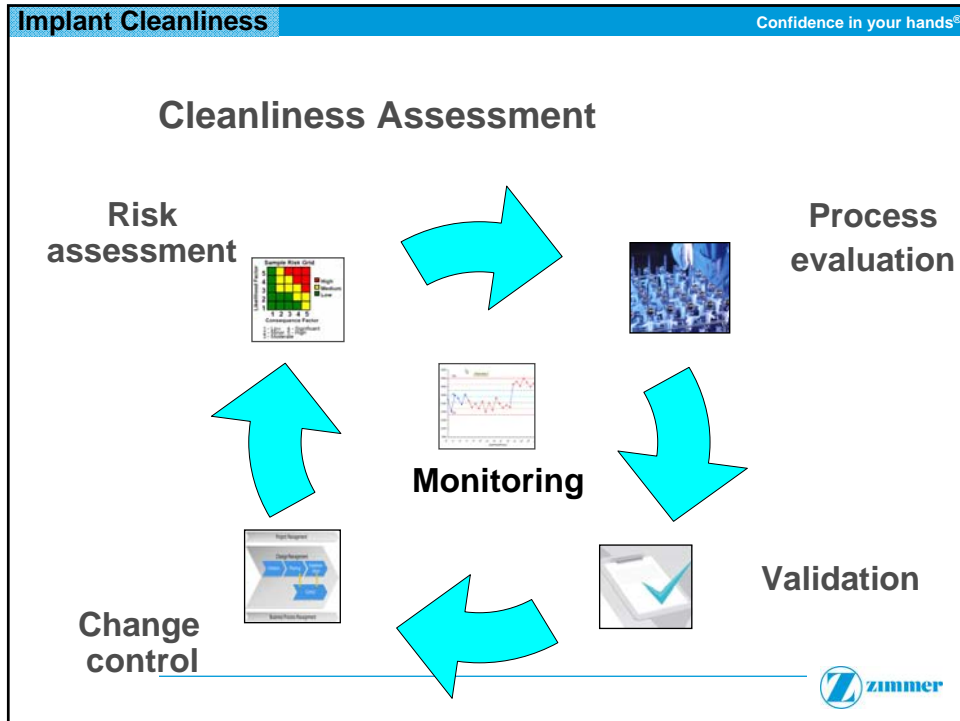
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## Introduction

1. Important steps for cleanliness assessment
2. Overview of test methods and evaluation
3. FTIR method for organic residues at low levels
4. Identification of residues by GC-MS

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### Which Test Method ?



Only 1 test method (ASTM 2459) for non bio residues has been published  
According to WK15532 more specific methods are required  
No standard for non water-soluble organics (e.g. oil residues)


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Different strategies, methods and specifications to assess cleanliness  
additional ASTM standards required

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Which test method is best?




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## Evaluation of Test Method

- Detectability of all potential residues
- Detection limit below specified cleanliness
- Compatibility of device with the method
- Quantitative (comparison with alarm / limit values)
- Accepted by authorities / standardized
- Costs and throughput time

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## Test Methods for cleanliness control I

	Technique	+	-
<b>Direct Analysis (Surface)</b>	Visual examination	<ul style="list-style-type: none"> <li>• Rapid</li> <li>• Inexpensive</li> <li>• No extraction</li> </ul>	<ul style="list-style-type: none"> <li>• Only large visible spots detectable</li> <li>• limited for complex surfaces</li> </ul>
	SEM/EDX XPS TOF-SIMS	<ul style="list-style-type: none"> <li>• Rapid identification</li> <li>• No extraction</li> </ul>	<ul style="list-style-type: none"> <li>• no quant. of total MD surface</li> <li>• limited for complex surfaces</li> </ul>
<b>Indirect Specific Analysis (Extraction)</b>	GC-MS ICP-MS	<ul style="list-style-type: none"> <li>• Identification of mixtures</li> <li>• Low LOD: ng/device</li> </ul>	<ul style="list-style-type: none"> <li>• Not universal</li> <li>• Expensive</li> <li>• Complex</li> </ul>


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### Test Methods for cleanliness control II

	Technique	+	-
<b>Indirect Universal Analysis (Extraction)</b>	<b>TOC</b> USP 643	<ul style="list-style-type: none"> <li>low LOD: 0.03 mg</li> <li>all water-soluble organics</li> </ul>	<ul style="list-style-type: none"> <li>no nonpolar organics</li> <li>recovery valid.</li> </ul>
	<b>FTIR</b> ASTM JAI13391	<ul style="list-style-type: none"> <li>low LOD: 0.03 mg</li> <li>nonpolar organics</li> </ul>	<ul style="list-style-type: none"> <li>polymer leachables</li> <li>recovery valid.</li> </ul>
	<b>Conductivity</b> USP 645	<ul style="list-style-type: none"> <li>inorganic and organic ions</li> <li>inexpensive</li> </ul>	<ul style="list-style-type: none"> <li>limited to ions</li> <li>recovery valid.</li> </ul>
	<b>Gravimetry</b> e.g. ASTM F2459	<ul style="list-style-type: none"> <li>most universal: all nonvolatiles</li> <li>Inexpensive</li> </ul>	<ul style="list-style-type: none"> <li>high LOD: 0.3 mg/device</li> <li>recovery valid.</li> </ul>
	<b>Particle count</b> USP 788	<ul style="list-style-type: none"> <li>low LOD: a few particles</li> </ul>	<ul style="list-style-type: none"> <li>no solubles</li> <li>recovery valid.</li> </ul>




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### Principle of Cleanliness Testing with Extraction



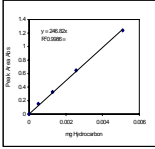
Complete immersion in a (non) polar solvent




Ultrasonic extraction of polar, non polar or particulate residues



Analysis with sensitive techniques



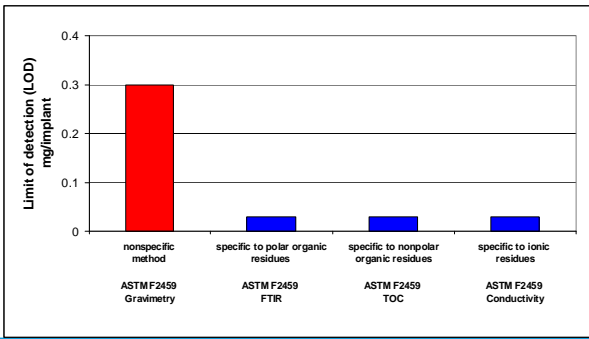
Quantification with a reference compound calibration




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## Limitation of ASTM F2459 / Gravimetry

- LOD of 0.3 mg not low enough for cleanliness assessment
- Differentiation between (inorganic / organic) not possible
- long-term experience for reproducible analysis required
- More sensitive methods (e.g. FTIR) 10 x lower LOD required



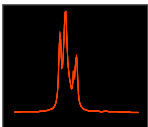


Method	LOD (mg/implant)
nonspecific method (ASTM F2459 Gravimetry)	0.3
specific to polar organic residues (ASTM F2459 FTIR)	~0.03
specific to nonpolar organic residues (ASTM F2459 TOC)	~0.03
specific to ionic residues (ASTM F2459 Conductivity)	~0.03



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## FTIR Method for Organic Residues

**Extraction acc. ASTM F2459 with carbon tetrachloride (CCl<sub>4</sub>)**

polymers:	1-10 min Ultrasonic (US) at room temperature (RT)
metals:	US / RT structure dependent
ceramics:	US / RT
Hydroxyapatite	US / RT


**Measurement of IR spectra by FTIR based on ASTM F1374-92<sup>1</sup>**

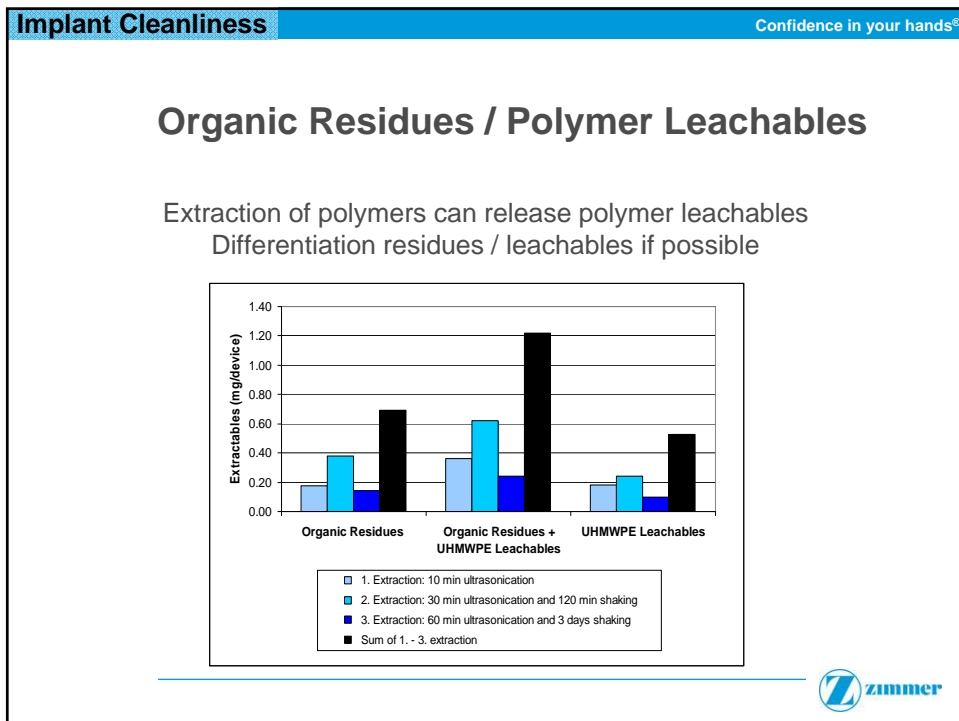
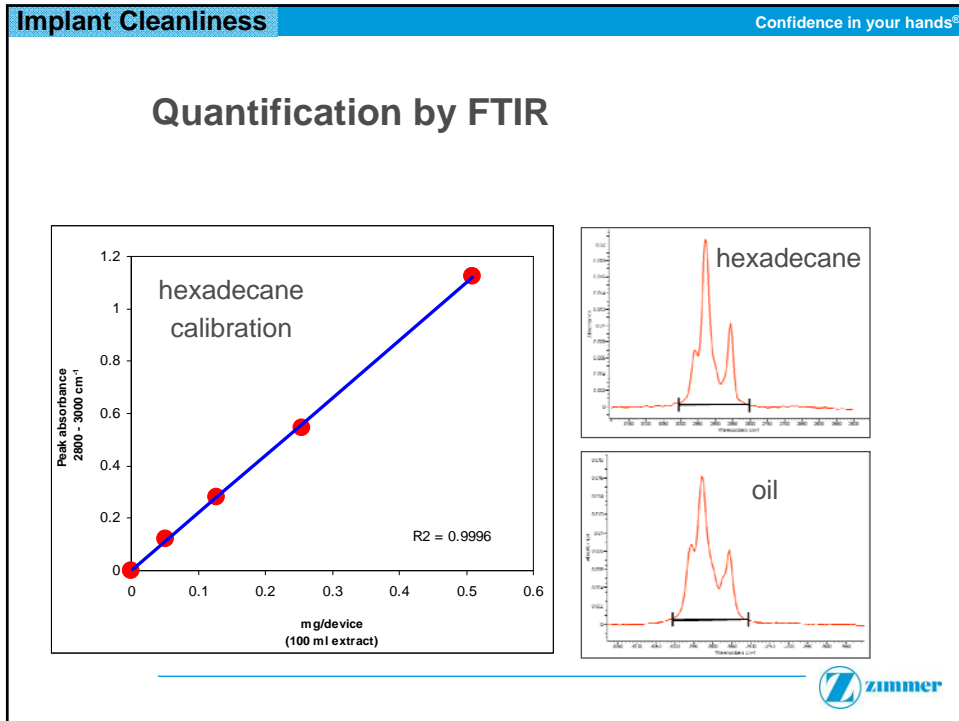
direct measurement of extract in transmission (1 cm cuvette)  
 recording spectra in the range from 2500 – 4000 cm<sup>-1</sup>  
 covers all extractable hydrocarbons (oil, cooling agents etc.)

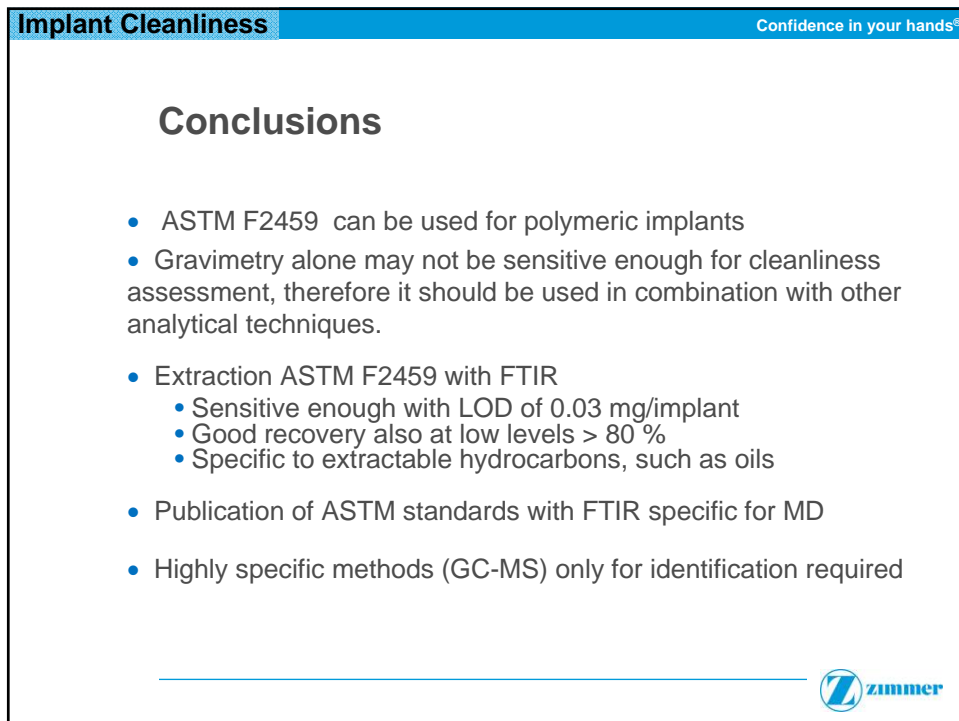
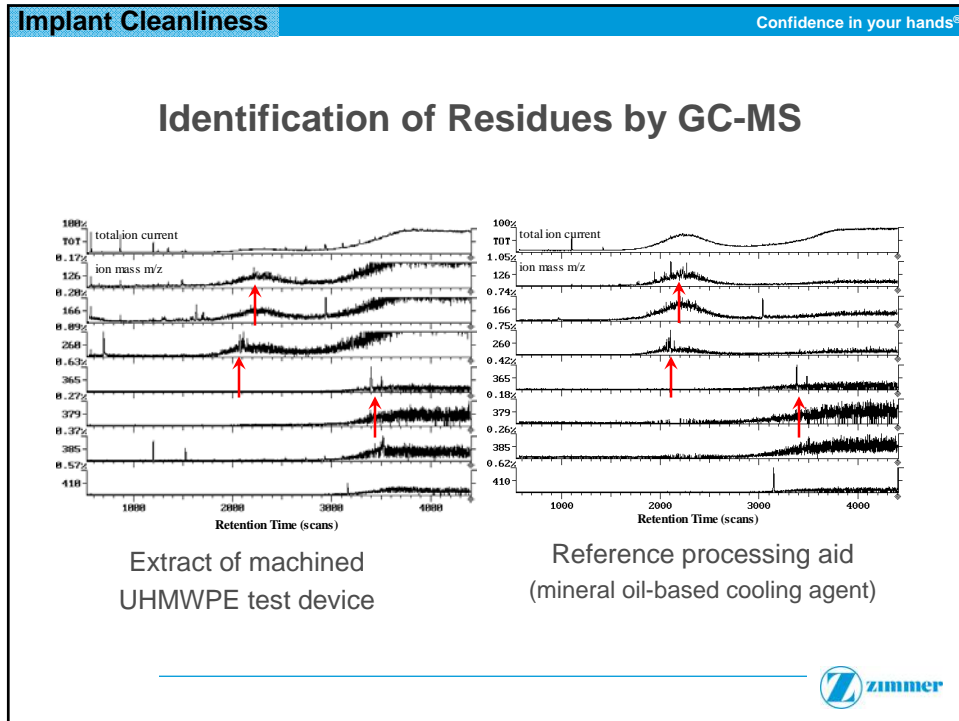
**Quantification**

integration of hydrocarbon peak (C-H) in the range from 2800 – 3000 cm<sup>-1</sup>  
 quantification against a reference hydrocarbon (hexadecane or reference oil)  
 results in mg/implant or mg/area

1) ASTM F1374-92 Standard Test Method for Ionic/Organic Extractables of Internal Surfaces-IC/GC/FTIR for Gas Distribution System Components (Ultra-High-Purity Gas Distribution Systems)







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**Thank you for your attention**



A black stick figure is shown from the side, holding its head with its right hand. A question mark is positioned above the figure's head, suggesting confusion or a question about the preceding information.

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